EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	5	test with pattern and opc and walsh	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:06
S2	18	pattern and opc and walsh	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:07
S3	13	S2 not S1	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:07
S4	865	pattern same walsh	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:07
S5	865	pattern same walsh	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:07
S6	3	pattern same walsh and opc	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:08
S7	122	opc test pattern layout synthesis	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/11/30 09:30
S8	1	("6952818").PN.	US-PGPUB; USPAT	OR	OFF	2007/11/30 09:33

EAST Search History

S9	91	S7 and "716"/$.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:30
S10	1	S9 and walsh	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/30 09:30
S11	1	(System method testing pattern sensitive algorithms semiconductor design).ti.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/11/30 09:53
S12	1531	walsh near4 (transform or matri$4)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/11/30 09:53
S13	132	S12 same pattern	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/11/30 13:16
S14	1	("6446248").PN.	US-PGPUB; USPAT	OR	OFF	2007/11/30 13:16